Angle-resolved photoemission spectroscopy (ARPES) is the premier technique for the determination of the electronic bandstructure of solids, and has found wide application for many classes of materials, such as oxides, semiconductors, metals, and low-dimensional materials and surfaces. Recently, ARPES has been extended to submicron dimensions through the development of nano-scale scanning X-ray beams, creating so-called nanoARPES endstations at synchrotrons around the world.

In this talk I will give an introduction to the nanoARPES at the MAESTRO beamline of the Advanced Light Source and present some recent results on 2D heterostructures including measurement of near magic angle bi-layer graphene and gated monolayer graphene devices.